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Table of Contents

Acknowledgement vii
Conference Chairs viii
Organizing Committee ix
Program Committee x
Corporate Supporters xi

Technical Papers

Proving the Capability of Arm IP for Functional Safety Applications 1
Asif Jafri (ARM) and Jung-Wook Kim (ARM)

Test Program Generator MicroTESK for RISC-V 6
Mikhail Chupilko (ISP RAS, Russia), Alexander Kamkin (ISP RAS, MSU, MIPT, HSE, Russia), Artem Kotsynyak (ISP RAS, Russia), Alexander Protsenko (ISP RAS, Russia), Sergey Smolov (ISP RAS, Russia), and Andrei Tatarnikov (HSE, Russia)

Fast Reliable Verification Methodology for RISC-V Without a Reference Model 12
Abdelfattah Munir (Department of Communications and Electronics, Ain Shams University, Cairo, Egypt), Mina Magdy (Mentor, a Siemens Business, Cairo, Egypt), Samer Ahmed (Department of Communications and Electronics, Cairo University, Giza, Egypt), Sherouk Nasr (Department of Communications and Electronics, Ain Shams University, Cairo, Egypt), Sameh El-Ashry (Department of Computer and Systems Engineering, Ain Shams University, Cairo, Egypt), and Ahmed Shalaby (Department of Computer Science, Faculty of Computers and Informatics, Benha University, Egypt)

Mining Security Critical Linear Temporal Logic Specifications for Processors 18
Calvin Deutschbein (University of North Carolina at Chapel Hill) and Cynthia Sturton (University of North Carolina at Chapel Hill)

A Perceptron-Inspired Technique for Hardware Obfuscation 24
Siroos Madani (University of Louisiana at Lafayette), Mohammad R. Madani (University of Louisiana at Lafayette), and Magdy Bayoumi (University of Louisiana at Lafayette)

How to Close Coverage 10x Faster using Portable Stimulus Standard - A Case Study .28
Shelly Henry (Microsoft) and Nirabh Regmi (Microsoft)

Application of Combinatorial Test (CT) Algorithm for Protocol and Hardware Feature Validation .31
Rekha Bangalore (Intel Corporation) and Raji M. Bandanapudi (Intel Corporation)

Multi-Master Validation Framework for Next Generation Automotive SOCs .35
Manish Kumar Agarwal (NXP Semiconductor), Amandeep Sharan (NXP Semiconductors), Mohammad Asif Khan (NXP Semiconductors), and Atul Gupta (NXP Semiconductors)

2018 FPGA Functional Verification Trends .40
Harry Foster (Mentor, A Siemens Business)

Getting Started on Co-Emulation: Transition your Design and Testbench to an Emulator .46
Jigar Savla (Juniper Networks, USA)

Automatic Debug Quantification for Workload Balance and Progress Tracking .52
Yanhua Cao (Advanced Micro Devices, Inc.), Osama Shoubber (Advanced Micro Devices, Inc.), and Pallavi Jesrani (Advanced Micro Devices, Inc.)

Advanced Regression Management for Post-Silicon Validation of Automotive SOCs .56
Ayushi Agarwal (NXP semiconductors), Pankaj Gupta (NXP semiconductors), and Atul Gupta (NXP semiconductors)

Efficient Methodology of Sampling UVM RAL During Simulation for SoC Functional Coverage .61
Sameh El-Ashry (Si-Vision LLC) and Ahmed Adel (Si-Vision LLC)

Different Reference Models for UVM Environment to Speed Up the Verification Time .67
Amr Moursi (Mentor, a Siemens Business, Cairo, Egypt), Romaisaa Samhoud (Mentor, a Siemens Business, Cairo, Egypt), Yaseen Kamal (Department of Communications and Electronics, Faculty of Engineering, Alexandria University, Alexandria, Egypt), Mazen Magdy (Department of Communications and Electronics, Faculty of Engineering, Alexandria University, Alexandria, Egypt), Sameh El-Ashry (Department of Computer and Systems Engineering, Ain Shams University, Cairo, Egypt), and Ahmed Shalaby (Department of Computer Science, Faculty of Computers and Informatics, Benha University, Egypt)

Transaction Based Speedup for Simulation Replay .73
Chetas Mapara (Advanced Micro Devices Inc.) and Priti Nagarajan (Advanced Micro Devices Inc.)

Pre-Silicon DFT Verification on SOC Slim Model .76
Pratheema Mohandoss (Intel Corporation) and Archana Rengaraj (Intel Corporation)

Schmoo Data Analysis Using Machine Language Algorithms .79
Rekha Bangalore Bangalore (Intel), Adeosun luwatosin Oluwatosin (Intel), and Kelvin K. Lam (Intel)

Author Index 87